

	Type	Hits	Search Text	DBs
1	BRS	3380	361/56	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
2	BRS	116	MOSFET same gate adj (leak leakage)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
3	BRS	29	MOSFET same gate adj (leak leakage) same substrate	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
4	BRS	1	MOSFET same gate adj (leak leakage) same substrate same gate adj voltage	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
5	BRS	0	MOSFET same gate adj (leak leakage) same substrate same drain adj voltage	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
6	BRS	1	MOSFET same gate adj (leak leakage) same drain adj voltage	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
7	BRS	3	MOSFET and gate adj (leak leakage) same drain adj voltage	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
8	BRS	29	MOSFET same gate adj (leak leakage) same gate same substrate	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
9	BRS	0	MOSFET same gate adj (leak leakage) same gate adj2 (bias biasing)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
10	BRS	11	6,064,158	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
11	BRS	13	5,864,162	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
12	BRS	15	5,847,516	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
13	BRS	16	MOSFET same source adj current same gate adj (bias biasing)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
14	BRS	123	MOSFET same source adj current same source adj voltage	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
15	BRS	2	MOSFET same source adj leak same source adj voltage	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
16	BRS	71	esd same MOSFET same trigger	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
17	BRS	24	esd same MOSFET same trigger same substrate	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB

	Time Stamp	Comments	Error Definition	Errors
1	2003/04/10 09:29			0
2	2003/04/10 09:40			0
3	2003/04/10 09:59			0
4	2003/04/10 09:35			0
5	2003/04/10 09:35			0
6	2003/04/10 09:36			0
7	2003/04/10 09:37			0
8	2003/04/10 09:46			0
9	2003/04/10 10:08			0
10	2003/04/10 10:01			0
11	2003/04/10 10:03			0
12	2003/04/10 10:03			0
13	2003/04/10 10:18			0
14	2003/04/10 10:28			0
15	2003/04/10 11:15			0
16	2003/04/10 11:45			0
17	2003/04/10 11:27			0

	Type	Hits	Search Text	DBs
18	BRS	26	esd same MOSFET same (trigger triggering) same substrate	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
19	BRS	17	("4595941" "4835416" "4890187" "4918563" "4922371" "4978867" "4980792" "4982113" "5041889" "5121007" "5124578" "5134314" "5189588" "5239440" "5287241" "5343352" "5345357").PN.	USPAT
20	BRS	17	("4595941" "4835416" "4890187" "4918563" "4922371" "4978867" "4980792" "4982113" "5041889" "5121007" "5124578" "5134314" "5189588" "5239440" "5287241" "5343352" "5345357").PN.	USPAT
21	BRS	8	5,852,541	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
22	BRS	6	5,959,488	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
23	BRS	14	4,609,488	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
24	BRS	24	4,609,931	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
25	BRS	32	esd same MOSFET same (leak leakage)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
26	BRS	12	esd same MOSFET same (leak leakage) same substrate	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
27	BRS	3	("5530612" "5539327" "5565790").PN.	USPAT
28	BRS	3	5903419.URPN.	USPAT
29	BRS	2730	361/111	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
30	BRS	1179	361/91.5	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
31	BRS	37	esd same (plurality multiple) adj (inputs outputs)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB

	Time Stamp	Comments	Error Definition	Errors
18	2003/04/10 11:28			0
19	2003/04/10 11:31			0
20	2003/04/10 11:35			0
21	2003/04/10 13:13			0
22	2003/04/10 13:47			0
23	2003/04/10 13:17			0
24	2003/04/10 13:17			0
25	2003/04/10 13:50			0
26	2003/04/10 16:44			0
27	2003/04/10 13:58			0
28	2003/04/10 14:23			0
29	2003/04/10 16:44			0
30	2003/04/11 09:10			0
31	2003/04/11 15:57			0

	Type	Hits	Search Text	DBs
32	BRS	5	5,751,507	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB

	Time Stamp	Comments	Error Definition	Errors
32	2003/04/11 15:57			0